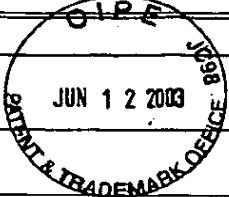
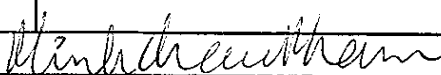


Sheet 1 of 1		FORM PTO 1449 (modified)		ATTY DOCKET NO. 2001-1792A		SERIAL NO. 10/000,304			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Yoko SUZUKI et al.					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				FILING DATE December 4, 2001				GROUP 3652	
Date Submitted to PTO: June 12, 2003									
U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
M	AA	2001/0011640	8/2001	Suzuki et al.					
↓	AB	4,967,295	10/1990	Yamauchi et al.					
M	AC	6,436,849	8/2002	Hasunuma et al.					
	AD								
	AE								
	AF								
	AG								
	AH								
	AI								
FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO		
M	AJ	1297882A1	4/2003	EP					
	AK								
	AL								
	AM								
	AN								
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)									
M	AO	Shoko ITO et al., "Wafer ambient control for Agile FAB", 0-7803-6731-6/01/\$10.00©2001 IEEE, pgs. 121-124.							
	AP								
	AQ								
<div style="border: 2px solid black; padding: 10px; width: fit-content; margin: 0 auto;"> RECEIVED JUN 16 2003 GROUP 3600 </div>									
EXAMINER 				DATE CONSIDERED 10/17/03					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1446 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: July 3, 2002

ATTY DOCKET NO.
2001-1792ASERIAL NO.
10/000,304APPLICANT
Yoko SUZUKI et al.FILING DATE
December 4, 2001GROUP
3652 1724

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PE	AA	5,346,518	9/1994	Baseman et al.			
8 3 2002	AB	6,040,680	3/2000	Toya et al.			
AC	5,380,503	1/95	Fuji et al.				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
AD	2000-174109	6/2000	JP				
AE	9-29020	2/1997	JP				
AF	6-291177	10/1994	JP				
AG	7-94577	4/1995	JP				
AI	617573A		EP				
AI	69401023C		DE				
AJ	11-195699	7/1999	JP				
AK	2000-223554	8/2000	JP				
AL	11-314703	11/1999	JP				
AM	11-40207	2/1999	JP				
AN	381356B		TW				
AO	0560379A1	9/1993	EP				
AP	6-29373	2/1994	JP				
AQ	69304570C		DE				
AR	2000-311936	11/2000	JP				

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.